

ISSUE: [July 2026](#)

Innovation, Collaboration, And Industry Leadership Headline The 2026 EOS/ESD Symposium

The [2026 EOS/ESD Symposium](#) is shaping up to be another outstanding gathering of the global EOS/ESD community, bringing together engineers, researchers, program managers, manufacturers, and industry leaders for a full week of technical education, collaboration, and networking.

Hosted by the EOS/ESD Association, the global standards and education organization, the symposium will feature an engaging technical program focused on the latest developments in electrostatic discharge protection, electrical overstress, advanced semiconductor technologies, manufacturing reliability, process assessment, and emerging applications of artificial intelligence in ESD analysis.

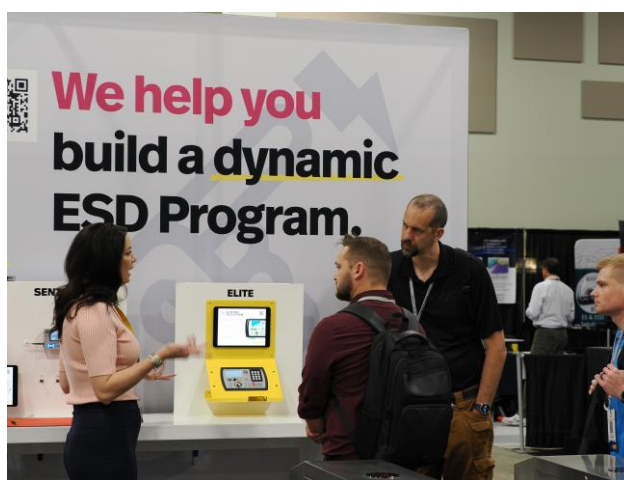
The week begins on Sunday, September 27, with the EOS/ESD Association Annual Meeting & Reception, welcoming attendees from around the world and setting the stage for an exciting week of professional exchange and industry engagement.

Monday's opening keynote, "Deep Neural Networks and Transfer Learning: Unlocking the Potential for ESD Data Analysis and Simulations," highlights one of the symposium's major themes for 2026—the growing role of artificial intelligence and advanced data analytics in EOS/ESD research and problem solving. Attendees will also receive an update on the 2027 ESDA Roadmap, providing valuable insight into future technology trends, industry priorities, and evolving challenges facing the electronics industry.

Throughout the week, the symposium program features a robust lineup of technical paper presentations, interactive seminars, discussion sessions, and industry networking opportunities. Technical sessions will explore a broad range of topics, including advanced CMOS technologies, ESD event detection, device reliability, latch-up performance, system-level ESD, manufacturing controls, and emerging protection strategies.

Interactive seminars continue to be a key highlight of the symposium experience, encouraging attendee participation and practical discussion around real-world engineering challenges. Sessions such as "Applying Air-discharge ESD to Conductors: Is it time to stop the madness?" and "Process Assessment—ESD Event Detection" are expected to generate lively technical dialogue among participants.

Tuesday's keynote session will focus on reliability risks in harsh radiation environments and the critical relationship between latch-up performance and radiation hardness. This session underscores the increasing complexity of modern electronic systems and the need for multidisciplinary reliability strategies.





Scenes from last year's symposium.

In addition to the strong technical content, attendees will have extensive opportunities to connect with industry peers and solution providers during networking breaks, exhibitor engagement activities, receptions, and the exhibit hall experience. Guided exhibitor tours and dedicated networking events are designed to help attendees discover new technologies, exchange ideas, and build valuable professional relationships.

The symposium will also recognize technical excellence through its Symposium Paper Awards Presentation and continue its long-standing tradition of fostering collaboration between academia, industry, and standards development experts.

Whether attendees are focused on semiconductor design, manufacturing operations, compliance programs, research, or reliability engineering, the 2026 EOS/ESD Symposium offers valuable education and practical insight for professionals across the electronics industry.

With its combination of cutting-edge technical content, interactive learning, and world-class networking opportunities, the 2026 EOS/ESD Symposium continues to serve as the premier international event dedicated to EOS/ESD awareness, research, and technology advancement.

Additional program details, technical sessions, and event information are available at www.esda.events.